Saeed Moghaddam

List of Publications by Year
in descending order

		2682572	2272923
6	11	2	4
papers	citations	h-index	g-index

6	6	6	3
all docs	docs citations	times ranked	citing authors

#	ARTICLE	IF	CITATIONS
1	A single-oscillator long-wave-length limit Sellmeier equation based fitting approach applied to the case of thin-film silicon and some of its more common alloys. Journal of Materials Science: Materials in Electronics, 2021, 32, 397-419.	2.2	1
2	Thin-film optical function acquisition from experimental measurements of the reflectance and transmittance spectra: a case study. Journal of Materials Science: Materials in Electronics, 2021, 32, 17033-17060.	2.2	0
3	A Sellmeier extended empirical model for the spectral dependence of the refractive index applied to the case of thin-film silicon and some of its more common alloys. Journal of Materials Science: Materials in Electronics, 2020, 31, 212-225.	2.2	2
4	Influence of the growth temperature on the spectral dependence of the optical functions associated with thin silicon films grown by ultra-high-vacuum evaporation on optical quality fused quartz substrates. Journal of Materials Science: Materials in Electronics, 2020, 31, 13186-13198.	2.2	2
5	A re-examination of experimental evidence on the spectral dependence of the optical transition matrix element associated with thin-film silicon. Journal of Materials Science: Materials in Electronics, 2019, 30, 9964-9972.	2.2	2
6	Empirical expressions for the spectral dependence of the refractive index for the case of thin-film silicon and some of its common alloys. Journal of Materials Science: Materials in Electronics, 2019, 30, 1637-1646.	2.2	4